|  |  |  | November 1992 <br> Revised January 1999 |
| :---: | :---: | :---: | :---: |
| SEMICONDUCTORTN |  |  |  |
| 74ABT899 |  |  |  |
| 9－Bit Lat with Par | chable Tra | ansceiver ator／Check | $r$ |
| General Description |  |  | －Ability to simultaneously generate and check parity |
| The ABT899 is a 9－bit to 9－bit parity transceiver with trans－ parent latches．The device can operate as a feed－through transceiver or it can generate／check parity from the 8 －bit data busses in either direction． |  |  | May be used in systems applications in place of the 543 and 280 <br> May be used in system applications in place of the 657 and 373 （no need to change $T / \overline{\mathrm{R}}$ to check parity） |
| The ABT899 features independent latch enables for the A－ to－B direction and the B－to－A direction，a select pin for ODD／EVEN parity，and separate error signal output pins for checking parity． |  |  | ■ Guaranteed output skew <br> ■ Guaranteed multiple output switching specifications <br> ■ Output switching specified for both 50 pF and 250 pF loads |
| Features |  |  | Guaranteed simultaneous switching noise level and dynamic threshold performance |
| －Latchable transceiver with output sink of 64 mA |  |  | ■ Guaranteed latchup protection |
| Option to select generate parity and check or ＂feed－through＂data／parity in directions A－to－B or B－to－A |  |  | High impedance glitch free bus loading during entire power up and power down cycle |
| Independent latch enables for A－to－B and B－to－A directions |  |  | －Nondestructive hot insertion capability <br> －Disable time less than enable time to avoid bus |
| －Select pin for ODD／EVEN parity <br> ■ ERRA and $\overline{\text { ERRB }}$ output pins for parity checking |  |  | contention |
| Ordering Code： |  |  |  |
| Order Number | Package Number | Package Description |  |
| 74ABT899CSC | M28B | 28－Lead Small Outline Integrated Circuit（SOIC），MS－013，0．300＂Wide Body |  |
| 74ABT899CMSA | MSA28 | 28－Lead Shrink Small Outline Package（SSOP），EIAJ TYPE II，5．3mm Wide |  |
| 74ABT899CQC | V28A | 28－Lead Plastic Lead Chip Carrier（PLCC），JEDEC MO－047，0．450＂Square |  |
| Devices also available in Tape and Reel．Specify by appending suffix letter＂$X$＂to the ordering code． |  |  |  |
| Connectio <br> APAR GBD $\overline{\text { ERRB }}$ SEL LEB BPAR | n Diagrams <br> Pin Assignment for PLCC <br> $A_{7} A_{6} A_{5} A_{4} A_{3} A_{2} A_{1}$ <br> 四回回回回回 |  |  |

Pin Descriptions

| Pin Names | Descriptions |
| :--- | :--- |
| $A_{0}-A_{7}$ | A Bus Data Inputs/Data Outputs |
| $B_{0}-B_{7}$ | B Bus Data Inputs/Data Outputs |
| APAR, BPAR |  |
| ODD/EVEN | A and B Bus Parity Inputs/Outputs <br> ODD/EVEN Parity Select, <br> Active LOW for EVEN Parity <br> Output Enables for A or B Bus, <br> Active LOW <br> GBA,$\overline{G A B}$ |
| $\overline{\text { SEL }}$ | Select Pin for Feed-Through or <br> Generate Mode, LOW for Generate <br> Mode |
| LEA, LEB | Latch Enables for A and B Latches, <br> HIGH for Transparent Mode |
| $\overline{\text { ERRA, ERRB }}$ | Error Signals for Checking Generated <br> Parity with Parity In, LOW if Error <br> Occurs |

## Functional Description

The ABT899 has three principal modes of operation which are outlined below. These modes apply to both the A-to-B and B -to-A directions.

- Bus $A(B)$ communicates to Bus $B(A)$, parity is generated and passed on to the $B(A)$ Bus as BPAR (APAR). If LEB (LEA) is HIGH and the Mode Select ( $\overline{\mathrm{SEL}}$ ) is LOW, the parity generated from $B[0: 7]$ ( $A[0: 7]$ ) can be checked and monitored by ERRB (ERRA).
- Bus $A(B)$ communicates to Bus $B(A)$ in a feed-through mode if SEL is HIGH. Parity is still generated and checked as ERRA and $\overline{E R R B}$ in the feed-through mode (can be used as an interrupt to signal a data/parity bit error to the CPU).
- Independent Latch Enables (LEA and LEB) allow other permutations of generating/checking (see Function Table below).


## Function Table



Functional Block Diagram


Absolute Maximum Ratings(Note 2)
Storage Temperature
Ambient Temperature under Bias
Junction Temperature under Bias Plastic
$\mathrm{V}_{\mathrm{CC}}$ Pin Potential to Ground Pin
Input Voltage (Note 3)
Input Current (Note 3)
Voltage Applied to Any Output in the Disable or Power-
Off State
in the HIGH State
Current Applied to Output
in LOW State (Max)
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
-0.5 V to +7.0 V
-0.5 V to +7.0 V
-30 mA to +5.0 mA
-0.5 V to +5.5 V
-0.5 V to $\mathrm{V}_{\mathrm{CC}}$
twice the rated $\mathrm{I}_{\mathrm{OL}}(\mathrm{mA})$

DC Latchup Source Current $\quad-500 \mathrm{~mA}$ Over Voltage Latchup (I/O)

10V

## Recommended Operating Conditions

| Free Air Ambient Temperature | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| :--- | ---: |
| Supply Voltage | +4.5 V to +5.5 V |
| Minimum Input Edge Rate $(\Delta \mathrm{V} / \Delta \mathrm{t})$ |  |
| $\quad$ Data Input | $50 \mathrm{mV} / \mathrm{ns}$ |
| Enable Input | $20 \mathrm{mV} / \mathrm{ns}$ |

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
Note 3: Either voltage limit or current limit is sufficient to protect inputs.

## DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | $\mathrm{V}_{\mathrm{cc}}$ | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | 2.0 |  |  | V |  | Recognized HIGH Signal |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage |  |  | 0.8 | V |  | Recognized LOW Signal |
| $\mathrm{V}_{\mathrm{CD}}$ | Input Clamp Diode Voltage |  |  | -1.2 | V | Min | $\mathrm{I}_{\mathrm{I}}=-18 \mathrm{~mA}$ (Non I/O Pins) |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\begin{aligned} & 2.5 \\ & 2.0 \end{aligned}$ |  |  | V | Min | $\mathrm{I}_{\mathrm{OH}}=-3 \mathrm{~mA},\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR $)$ <br> $\mathrm{I}_{\mathrm{OH}}=-32 \mathrm{~mA},\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR $)$ |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage |  |  | 0.55 | V | Min | $\mathrm{l}_{\mathrm{OL}}=64 \mathrm{~mA},\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR) |
| $\mathrm{V}_{\text {ID }}$ | Input Leakage Test | 4.75 |  |  | V | 0.0 | $\mathrm{I}_{\mathrm{ID}}=1.9 \mu \mathrm{~A}, \text { (Non-I/O Pins) }$ <br> All Other Pins Grounded |
| $\overline{I_{\mathrm{H}}}$ | Input HIGH Current |  |  | 5 | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \hline \mathrm{V}_{\mathrm{IN}}=2.7 \mathrm{~V}(\text { Non-I/O Pins) }(\text { Note } 4) \\ & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{CC}}(\text { Non-I/O Pins }) \end{aligned}$ |
| $\mathrm{I}_{\mathrm{BVI}}$ | Input HIGH Current <br> Breakdown Test |  |  | 7 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {IN }}=7.0 \mathrm{~V}$ (Non-I/O Pins) |
| $\mathrm{I}_{\text {BVIT }}$ | Input HIGH Current Breakdown Test (I/O) |  |  | 100 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {IN }}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR $)$ |
| ILL | Input LOW Current |  |  | -5 | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=0.5 \mathrm{~V} \text { (Non-I/O Pins) (Note 4) } \\ & \mathrm{V}_{\mathrm{IN}}=0.0 \mathrm{~V} \text { (Non-//O Pins) } \end{aligned}$ |
| $\overline{\mathrm{I}_{\mathrm{H}}+\mathrm{I}_{\text {OzH }}}$ | Output Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | 0V-5.5V | $\begin{aligned} & \mathrm{V}_{\mathrm{OUT}}=2.7 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) ; \\ & \overline{\mathrm{GAB}} \text { and } \overline{\mathrm{GBA}}=2.0 \mathrm{~V} \end{aligned}$ |
| $I_{\text {IL }}+\mathrm{I}_{\text {OZL }}$ | Output Leakage Current |  |  | -50 | $\mu \mathrm{A}$ | 0V-5.5V | $\begin{aligned} & \mathrm{V}_{\mathrm{OUT}}=0.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) \\ & \overline{\mathrm{GAB}} \text { and } \overline{\mathrm{GBA}}=2.0 \mathrm{~V} \end{aligned}$ |
| Ios | Output Short-Circuit Current | -100 |  | -275 | mA | Max | $\mathrm{V}_{\text {OUT }}=0 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR $)$ |
| $\mathrm{I}_{\text {CEX }}$ | Output HIGH Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}\left(\mathrm{A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR $)$ |
| $\mathrm{I}_{\text {zz }}$ | Bus Drainage Test |  |  | 100 | $\mu \mathrm{A}$ | 0.0V | $\mathrm{V}_{\text {OUT }}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right.$, APAR, BPAR); All Others GND |
| $\stackrel{I_{\text {CCH }}}{ }$ | Power Supply Current |  |  | 250 | $\mu \mathrm{A}$ | Max | All Outputs HIGH |
| $\mathrm{I}_{\text {CCL }}$ | Power Supply Current |  |  | 34 | mA | Max | All Outputs LOW, ERRA/B = HIGH (Note 5) |
| $\mathrm{I}_{\text {CCz }}$ | Power Supply Current |  |  | 250 | $\mu \mathrm{A}$ | Max | Outputs 3-STATE All Others at $\mathrm{V}_{\mathrm{CC}}$ or GND |
| ${ }^{\text {CCT }}$ | Additional $\mathrm{ICC}^{\text {/lnput }}$ |  |  | 2.5 | mA | Max | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\text {CC }}-2.1 \mathrm{~V}$ All Others at $\mathrm{V}_{\text {cC }}$ or GND |
| ${ }_{\text {CCD }}$ | Dynamic I ICc: No Load (Note 4) |  |  | 0.4 | $\mathrm{mA} / \mathrm{MHz}$ | Max | Outputs Open <br> $\overline{\mathrm{GAB}}$ or $\overline{\mathrm{GBA}}=\mathrm{GND}, \mathrm{LE}=\mathrm{HIGH}$ <br> Non-I/O = GND or VCC <br> One bit toggling, $50 \%$ duty cycle |
| Note 4: Guaranteed, but not tested. <br> Note 5: Add 3.75 mA for each ERR LOW. |  |  |  |  |  |  |  |

## DC Electrical Characteristics

(PLCC package)

| Symbol | Parameter | Min | Typ | Max | Units | $\mathrm{V}_{\mathrm{cc}}$ | $\begin{gathered} \text { Conditions } \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \mathrm{R}_{\mathrm{L}}=500 \Omega \end{gathered}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {OLP }}$ | Quiet Output Maximum Dynamic $\mathrm{V}_{\text {OL }}$ |  | 0.8 | 1.1 | V | 5.0 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (Note 6) |
| $\mathrm{V}_{\text {OLV }}$ | Quiet Output Minimum Dynamic $\mathrm{V}_{\text {OL }}$ | -1.3 | -0.8 |  | V | 5.0 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (Note 6) |
| $\mathrm{V}_{\text {OHV }}$ | Minimum HIGH Level Dynamic Output Voltage | 2.5 | 3.0 |  | V | 5.0 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (Note 8) |
| $\mathrm{V}_{\text {HD }}$ | Minimum HIGH Level Dynamic Input Voltage | 2.2 | 1.8 |  | V | 5.0 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (Note 7) |
| $\mathrm{V}_{\text {ILD }}$ | Maximum LOW Level Dynamic Input Voltage |  | 0.8 | 0.5 | V | 5.0 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (Note 7) |

Note 6: Max number of outputs defined as ( n ). $\mathrm{n}-1$ data inputs are driven OV to 3 V . One output at LOW. Guaranteed, but not tested.
Note 7: Max number of data inputs ( n ) switching. $\mathrm{n}-1$ inputs switching 0 V to 3 V . Input-under-test switching: 3 V to threshold ( $\mathrm{V}_{\text {ILD }}$ ), 0 V to threshold ( $\mathrm{V}_{\text {IHD }}$ ). Guaranteed, but not tested.
Note 8: Max number of outputs defined as ( n ). $\mathrm{n}-1$ data inputs are driven 0 V to 3 V . One output HIGH. Guaranteed, but not tested.

## AC Electrical Characteristics

| Symbol | Parameter | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Max |  |
| ${ }_{\text {tpLH }}$ | Propagation Delay | 1.5 | 3.0 | 4.8 | 1.5 | 4.8 | ns |
| $\mathrm{t}_{\text {PHL }}$ | $A_{n}$, to $B_{n}$ | 1.5 | 3.5 | 4.8 | 1.5 | 4.8 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 2.5 | 5.9 | 9.2 | 2.5 | 9.2 | ns |
| $\mathrm{t}_{\text {PHL }}$ | $A_{n}, B_{n}$ to BPAR, APAR | 2.5 | 5.8 | 9.2 | 2.5 | 9.2 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 2.5 | 5.4 | 8.5 | 2.5 | 8.5 | ns |
| $\mathrm{t}_{\text {PHL }}$ | $A_{n}, B_{n}$ to ERRA, $\overline{\text { ERRB }}$ | 2.5 | 5.4 | 8.5 | 2.5 | 8.5 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 1.5 | 3.7 | 6.0 | 1.5 | 6.0 | ns |
| $\mathrm{t}_{\text {PHL }}$ | APAR, BPAR to $\overline{\text { ERRA, }}$, ERRB | 1.5 | 3.7 | 6.0 | 1.5 | 6.0 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 2.0 | 4.4 | 6.9 | 2.0 | 6.9 | ns |
| $\mathrm{t}_{\text {PHL }}$ | ODD/EVEN to APAR, BPAR | 2.0 | 4.4 | 6.9 | 2.0 | 6.9 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 1.8 | 4.0 | 6.0 | 1.8 | 6.0 | ns |
| $\mathrm{t}_{\text {PHL }}$ | ODD/EVEN to ERRA, ERRB | 1.8 | 4.0 | 6.0 | 1.8 | 6.0 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 1.5 | 3.8 | 6.0 | 1.5 | 6.0 | ns |
| $\mathrm{t}_{\text {PHL }}$ | SEL to APAR, BPAR | 1.5 | 3.8 | 6.0 | 1.5 | 6.0 |  |
| $\mathrm{t}_{\text {PL }}$ | Propagation Delay | 1.5 | 3.2 | 4.6 | 1.5 | 4.6 | ns |
| $\mathrm{t}_{\text {PHL }}$ | LEA, LEB to $\mathrm{B}_{\mathrm{n}}, \mathrm{A}_{\mathrm{n}}$ | 1.5 | 3.2 | 4.6 | 1.5 | 4.6 |  |
| ${ }^{\text {t PLH }}$ | Propagation Delay | 2.5 | 5.9 | 8.8 | 2.5 | 8.8 |  |
| $\mathrm{t}_{\text {PHL }}$ | LEA, LEB to BPAR, APAR Generate Mode | 2.5 | 5.7 | 8.8 | 2.5 | 8.8 | ns |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 1.5 | 3.6 | 5.1 | 1.5 | 5.1 | ns |
| $\mathrm{t}_{\text {PHL }}$ | LEA, LEB to BPAR, APAR, Feed Thru Mode | 1.5 | 3.6 | 5.1 | 1.5 | 5.1 |  |
| ${ }_{\text {tPLH }}$ | Propagation Delay | 1.6 | 5.4 | 8.4 | 1.6 | 8.4 | ns |
| $\mathrm{t}_{\text {PHL }}$ | LEA, LEB to ERRA, ERRB | 1.6 | 5.4 | 8.4 | 1.6 | 8.4 |  |
| ${ }_{\text {t }}{ }_{\text {PZH }}$ | Output Enable Time | 1.5 | 3.6 | 6.0 | 1.5 | 6.0 | ns |
| $t_{\text {PZL }}$ | $\overline{\mathrm{GBA}}$ or $\overline{\mathrm{GAB}}$ to $\mathrm{A}_{n}$, APAR or $B_{n}$, BPAR | 1.5 | 3.4 | 6.0 | 1.5 | 6.0 |  |
| $\mathrm{t}_{\text {PHZ }}$ | Output Disable Time | 1.0 | 4.0 | 6.0 | 1.0 | 6.0 | ns |
| tplz | $\overline{\text { GBA }}$ or $\overline{\text { GAB }}$ to $A_{n}$, APAR or $B_{n}$, BPAR | 1.0 | 3.3 | 6.0 | 1.0 | 6.0 |  |
| tPLHtPHL | Propagation Delay | 1.5 | 3.3 | 5.4 | 1.5 | 5.4 | ns |
|  | APAR to BPAR, BPAR to APAR | 1.5 | 3.8 | 5.4 | 1.5 | 5.4 |  |

$\square$


## AC Operating Requirements

| Symbol | Parameter | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max |  |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{s}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{s}}(\mathrm{~L}) \end{aligned}$ | Setup Time, HIGH or LOW An, APAR to LEA or $B_{n}$, BPAR to LEB | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ |  | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ |  | ns |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{H}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{H}}(\mathrm{~L}) \end{aligned}$ | Hold Time, HIGH or LOW An, APAR to LEA or $\mathrm{B}_{\mathrm{n}}$, BPAR to LEB | $\begin{aligned} & 1.0 \\ & 1.0 \end{aligned}$ |  | $\begin{aligned} & \hline 1.0 \\ & 1.0 \end{aligned}$ |  | ns |
| $t_{w}(\mathrm{H})$ | Pulse Width, HIGH LEA or LEB | 3.0 |  | 3.0 |  | ns |




| Skew <br> (PLCC package) (Note 2) |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Symbol | Parameter | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ <br> 9 Outputs Switching <br> (Note 19) | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=250 \mathrm{pF} \end{gathered}$ <br> 9 Outputs Switching (Note 20) | Units |
|  |  | Max | Max |  |
| toshl <br> (Note 21) | Pin to Pin Skew HL Transitions | 1.0 | 2.0 | ns |
| $\mathrm{t}_{\mathrm{OSLH}}$ <br> (Note 21) | Pin to Pin Skew <br> LH Transitions | 1.1 | 2.1 | ns |
| $t_{P S}$ <br> (Note 22) | $\begin{aligned} & \text { Duty Cycle } \\ & \text { LH-HL Skew } \end{aligned}$ | 2.0 | 3.5 | ns |
| $\mathrm{t}_{\mathrm{OST}}$ <br> (Note 21) | Pin to Pin Skew LH/HL Transitions | 2.0 | 3.5 | ns |
| $t_{P V}$ <br> (Note 23) | Device to Device Skew LH/HL Transitions | 3.0 | 4.0 | ns |
| Note 19: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-toHIGH, HIGH-to-LOW, etc.). <br> Note 20: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. <br> Note 21: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW ( $\mathrm{t}_{\mathrm{OSHL}}$ ), LOW to HIGH ( $\mathrm{t}_{\mathrm{OSLH}}$ ), or any combination switching LOW to HIGH and/or HIGH to LOW (tost). This specification is guaranteed but not tested. Skew applies to propagation delays individually; i.e., $A_{n}$ to $B_{n}$ separate from LEA to $A_{n}$. <br> Note 22: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. <br> Note 23: Propagation delay variation for a given set of conditions (i.e., temperature and $\mathrm{V}_{\mathrm{CC}}$ ) from device to device. This specification is guaranteed but not tested. |  |  |  |  |

## Capacitance

| Symbol | Parameter | Typ | Units | Conditions <br> $\mathbf{T}_{\mathbf{A}}=\mathbf{2 5}{ }^{\circ} \mathbf{C}$ |
| :--- | :--- | :---: | :---: | :---: |
| $\mathrm{C}_{\mathrm{IN}}$ | Input Pin Capacitance | 5.0 | pF | $\mathrm{V}_{\mathrm{CC}}=0 \mathrm{~V}$ |
| $\mathrm{C}_{/ / \mathrm{O}}$ (Note 24) | Output Capacitance | 11.0 | pF | $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}$ |

[^0]
## 74ABT899


$\mathrm{A}_{\mathrm{n}}$, APAR $\rightarrow \mathrm{B}_{\mathrm{n}}$, BPAR
$\left(B_{n}\right.$, BPAR $\rightarrow A_{n}$, APAR $)$
FIGURE 1.

$\mathrm{A}_{\mathrm{n}} \rightarrow$ BPAR
( $\mathrm{B}_{\mathrm{n}} \rightarrow$ APAR)
FIGURE 2.

$$
\mathrm{A}_{\mathrm{n}} \rightarrow \overline{\mathrm{ERRA}}
$$



$$
\left(\mathrm{B}_{\mathrm{n}} \rightarrow \overline{\mathrm{ERRB}}\right)
$$

FIGURE 3.


[^1]O/E $\rightarrow$ ERRB
FIGURE 4.



AC Loading
FIGURE 15. Standard AC Test Load


FIGURE 16.

Input Pulse Requirements

| Amplitude | Rep. Rate | $\mathbf{t}_{\mathbf{w}}$ | $\mathbf{t}_{\mathbf{r}}$ | $\mathbf{t}_{\mathbf{f}}$ |
| :---: | :---: | :---: | :---: | :---: |
| 3.0 V | 1 MHz | 500 ns | 2.5 ns | 2.5 ns |

FIGURE 17. Test Input Signal Requirements

## AC Waveforms



FIGURE 18. Propagation Delay Waveforms for Inverting and Non-Inverting Functions


FIGURE 19. Propagation Delay, Pulse Width Waveforms


FIGURE 20. 3-STATE Output HIGH and LOW Enable and Disable Times


Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450" Square Package Number V28A

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[^2]
[^0]:    Note 24: $\mathrm{C}_{/ / \mathrm{O}}$ is measured at frequency, $\mathrm{f}=1 \mathrm{MHz}$, per MIL-STD-883B, Method 3012.

[^1]:    $\mathrm{O} / \mathrm{E} \rightarrow \overline{\mathrm{ERRA}}$

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